

AIDAINNOVA ANUAL MEETING 2024 LATEST RESULTS OF THE MONOPIX DEVELOPMENT LINES

Fabian Hügging on behalf of the Monopix testing teams

Mar 19th 24

Fabian Hügging – AlDAinnova Annual Meeting, Catania



- Designed in 180 nm TowerSemiconductor CMOS technology
- 2x2 cm² chip size
 - = 33.04x33.04 μ m² pixel pitch
- Small charge collection electrode relative to pixel pitch
- Full scale column length with column-drain R/O architecture
- Substrate resistivity >1 kΩcm
- Baseline for a new DMAPS developed for the Belle II VTX upgrade





TJ-Monopix2 Specifications

- Improved front-end to lower noise and threshold
 - TJ-Monopix1 ~350 e- THR and ~16 e⁻ noise
 - Observed RTS noise tail
- 7 bit ToT information @ 25 ns
- 3 bit in-pixel threshold tuning
 - More in-pixel logic at smaller pixel size
- Triggerless readout
- 4 front-end variations based on proven design from predecessor:
 - Cascoded version
 - AC coupled (HV) front-ends biased via n-well





Laboratory Measurements

- Extract mean tuned **threshold of ~250 e**⁻ and mean **ENC of ~6 e**⁻ from s-curve scan
 - Sufficient for excellent hit-detection efficiency (MIP charge MPV >2500 e⁻)
 - Threshold dispersion significantly reduced by 3 bit in-pixel trimming
 - No RTS noise tail





Threshold Oscillation

- Threshold depends on arrival time of signal (leading edge)
 - Amplitude O(50 e⁻) → Factor 10 larger than ENC
 - Dominant oscillation frequency roughly 5 MHz
- LE/TE sampled with 40 MHz clock in pixel
 - Bits of counter toggle in $\frac{40 MHz}{4/8/16/...}$
 - 4/8/10/...
- Peak of pre-amplifier transfer function 2-10 MHz
 - Very sensitive to frequency of counter bit toggling
 - Cross-talk cannot be mitigated while LE/TE sampling
- Workaround for (injection based) scans:
 - Reset of 40 MHz clock with respect to injection
 - Disable LE/TE sampling and charge measurement





TJ-Monopix2 Hit Detection Efficiency

- Comparison of front-end variations for epi substrate with gap in n-layer
 - Measured at approx. 250 e⁻ threshold for all samples
 - DC coupled at -6 V bias voltage (left, middle), AC coupled +15 V bias voltage (right)
 - Uniform hit detection efficiency >99% with no losses in pixel edges





- Measure delay between scintillator and HitOr signal with 640 MHz clock
- Estimate in-time ratio of hits in given time window of trigger distance distribution
- For 30 µm epi chip with n-gap modification and standard front-end:
 - **99.68% within 25 ns** (ATLAS BX frequency) In-time ratio Corrected scintillator-HitOr delay 1.00 10^{4} 120 0.95 100 10³ Ratio of in-time hits 60 50 50 80 [rigger delay [ns] 10² 10² 40 20 101 0.80 0 -20 100 0.75 20 15 25 30 500 1000 1500 2000 2500 3000 Seed charge (time over threshold) [ns] Time since trigger [ns]



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25 ns: (99.68 ± 0.01) %

45

50

35

40

20 ns: $(99.52 \pm 0.01)\%$

 $15 \text{ ns}: (98.99 \pm 0.01)\%$



In-pixel Signal Propagation

- Study in-pixel timing with telescope tracking data
- Investigate trigger delay relative to charge collection electrode
 - Electrodes indicated as white dot
- Up to 3.5 ns difference in delay due to charge propagation time to small electrode





- Designed in 150 nm LFoundry CMOS technology
- 2x1 cm² chip size
 - 50x150 μ m pixel pitch
- Large charge collection electrode relative to pixel pitch
- Full scale column length with column-drain R/O architecture
- Substrate resistivity >2 kΩcm





LF-Monopix2 Specifications

- Full in-pixel electronics while reducing the pixel pitch by 40% of predecessor
- 6 bit ToT information @ 25 ns
- 4 bit in-pixel threshold tuning
- 6 front-end variations available
 - Differing in CSA, feedback capacitance, tuning
- Proton irradiated samples up to 2e15 neq/cm² available (100 μm, backside processed)
 - Not powered during irradiation
 - Annealed 80 min @ 60 °C



LF-Monopix2 (Feb 2021)



Leakage Current and Gain

- Measure leakage current per cm² at -20 °C environmental temperature
 - Non-irradiated at room temperature
- Breakdown at ~460 V for non-irradiated sensors
- At 100 V bias voltage:
 - Increase in leakage current ~5 μA/cm² per irradiation step of 1e15 neq/cm² fluence



I-V curve comparison @ different fluences



- Operated in controlled laboratory environment @ -20 °C
- Tune-able to approx. 2 ke⁻ mean threshold at all irradiation steps
 - Expected charge MPV of MIP at full depletion around 6 ke⁻
- Ca. 40% increase in ENC per irradiation step of 1e15 neq/cm² fluence





Depletion Depth of LF-Monopix2

- Extract calibrated charge MPV from Landau shaped beam spectrum
 - Measured with 5 GeV electrons at DESY
- Full depletion reached around 200 V after irradiation to 2e15 neq/cm²
 - Non-irradiated sensors fully depleted at 15-20 V







Hit Detection Efficiency Studies

- After **2e15 neq/cm²** fluence still >99 % hit-detection efficiency
 - Measured >98 % mean in-time efficiency within 25 ns window —
 - Measured at 2 ke⁻ threshold and 300 V bias (full depletion) _
 - Almost 1 % masked pixels due to high ENC —



300

Hit-detection efficiency vs bias voltage

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In-Time Efficiency for Higher Gain

- Compare to pixels with smaller feedback capacitance
 - Verified larger gain by measurement (at 1e15 neq/cm²)
- Higher signal gain improves timing performance
 - Mean in-time efficiency of 99.6% @ 2e15 neq/cm²
 - Only 0.5% pixels masked (smaller matrix)

In-pixel, in-time efficiency (mean 99.60% @ 2e15 neq/cm²)









Conclusion and Outlook

- Non-irradiated TJ-Monopix2 show hit-detection efficiencies >99.9%
 - More than 99% of hits registered within 25 ns
- LF-Monopix2 fully operational after proton irradiation to 2e15 neq/cm²
 - >99% hit detection efficiency with ~1 % masked pixels due to high ENC

Upcoming measurements:

- Studies with neutron irradiated samples
- TID irradiation campaign in the next month(s)

Recent Publications:

- Test-beam performance of protonirradiated, large-scale DMAPS in 150nm CMOS technology (VERTEX23) DOI: 10.22323/1.448.0043
- Timing performance of monolithic CMOS pixel detector front-end inn 180nm technology (PACET24) (accepted, to be published)
- Cross-talk of a large-scale DMAPS in 180nm CMOS technology (HSTD23) (Submitted, under revision)



Thank you for your attention!

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